

# EE671: VLSI DESIGN

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# LECTURE – 36

## DRAM & OTHER MEMORIES

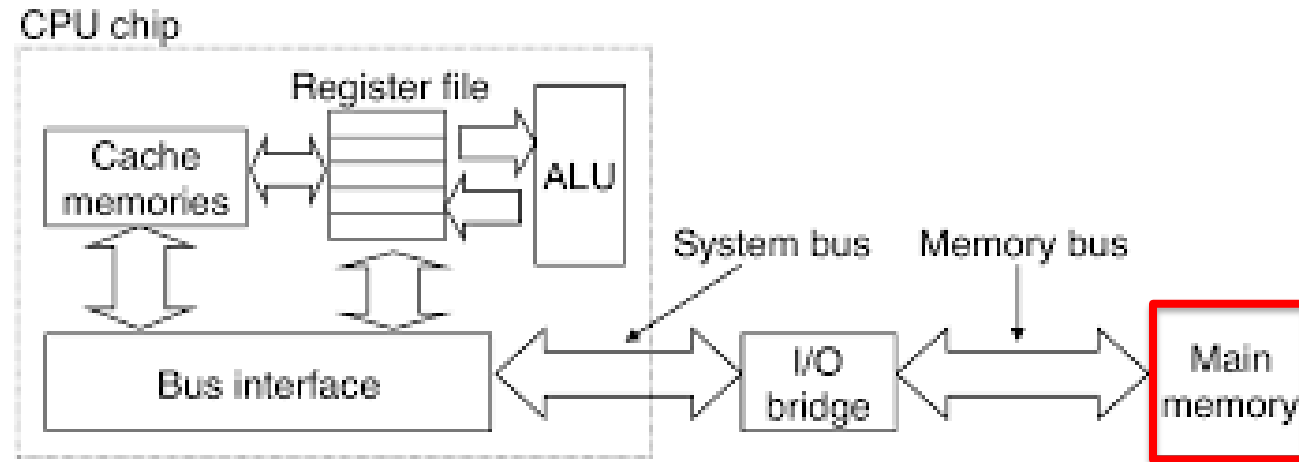
# MEMORY

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- ❑ SRAM: Digital (binary data) memory
- ❑ Is there an analog memory?
  - ❑ How about inductors and capacitors?
- ❑ Can we use capacitor as a memory?
  - ❑ DRAM: Dynamic RAM
  - ❑ What is dynamic?
- ❑ SRAM: Static RAM (volatile)
  - ❑ Unless you turn-off power, data is retained
- ❑ DRAM: Dynamic RAM (also volatile)
  - ❑ During power-on, if you do not do read/write operation, data is lost
  - ❑ Has to be dynamically refreshed!



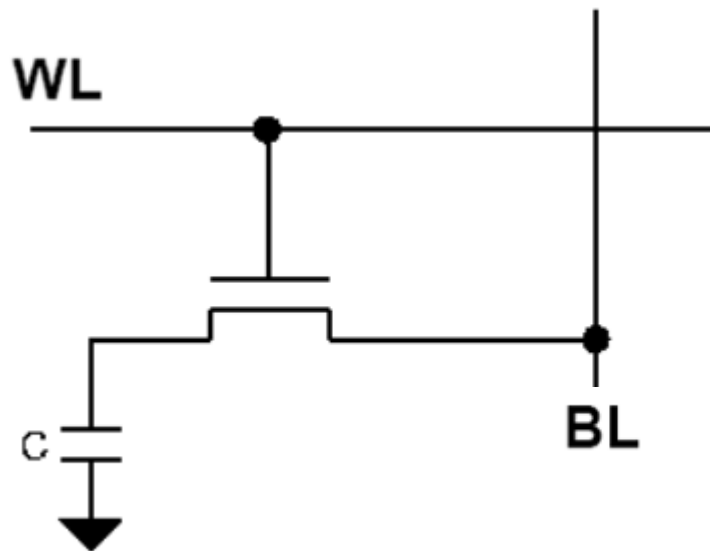
# MEMORY HIERARCHY IN PROCESSORS



	Capacity	Latency	Cost/GB	
Register	1000s of bits	20 ps	\$\$\$\$	Processor Datapath
SRAM	~10 KB-10 MB	1-10 ns	~\$1000	
DRAM	~10 GB	80 ns	~\$10	
Flash*	~100 GB	100 us	~\$1	Memory Hierarchy
Hard disk*	~1 TB	10 ms	~\$0.10	
				I/O subsystem

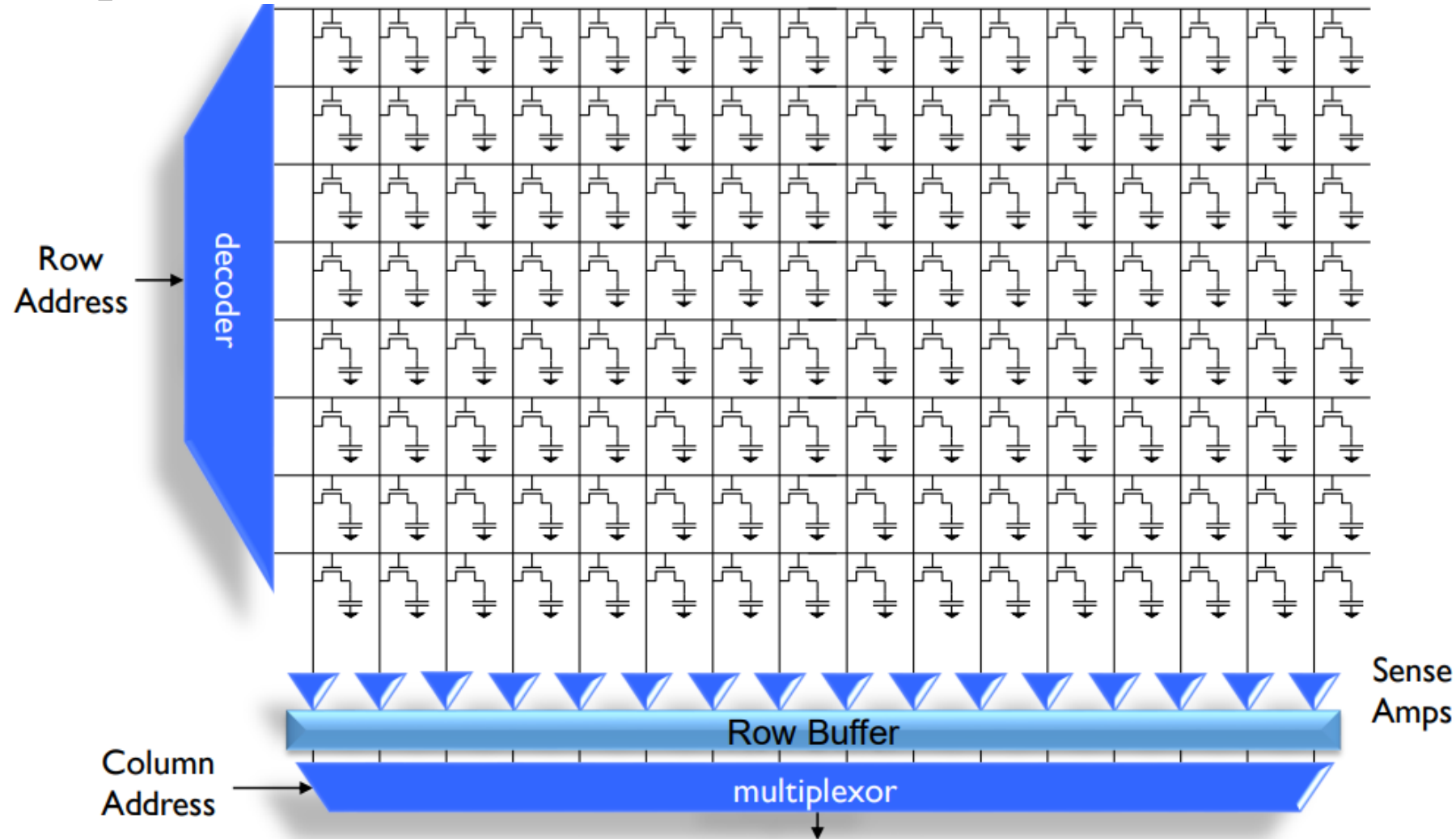
\* non-volatile (retains contents when powered off)





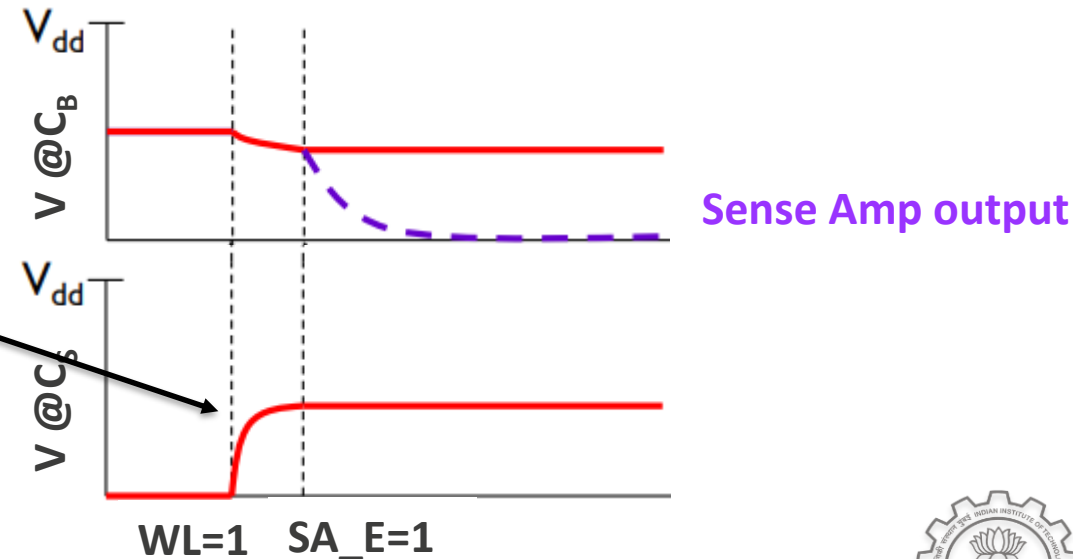
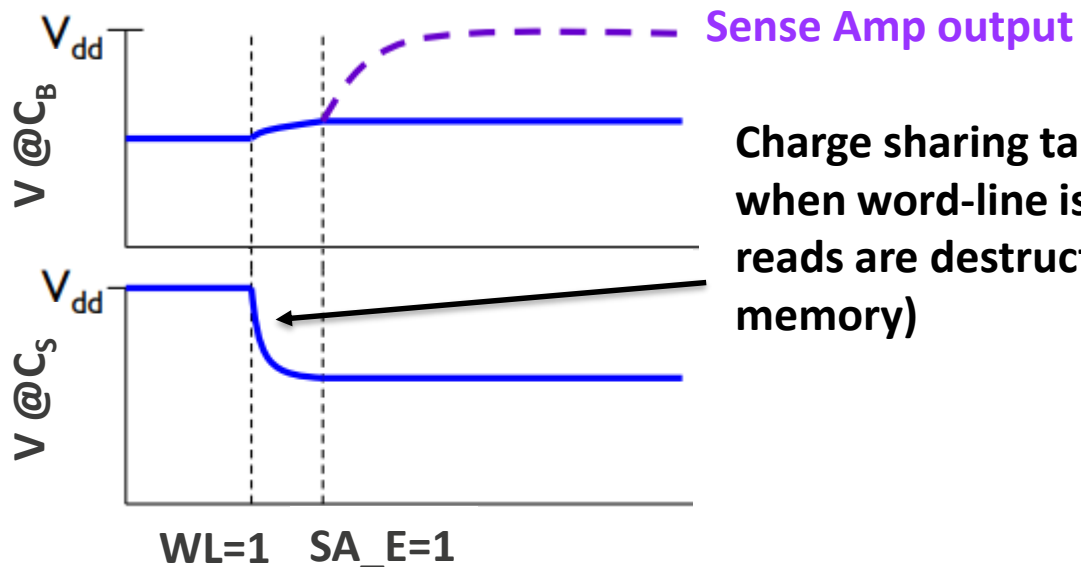
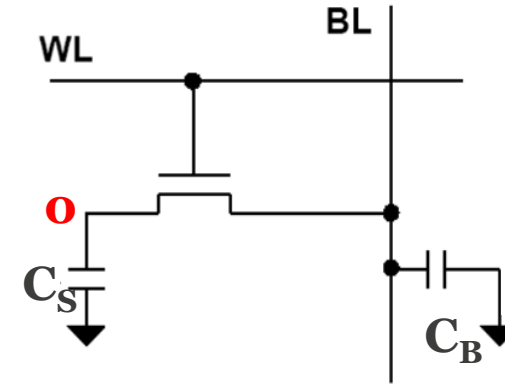
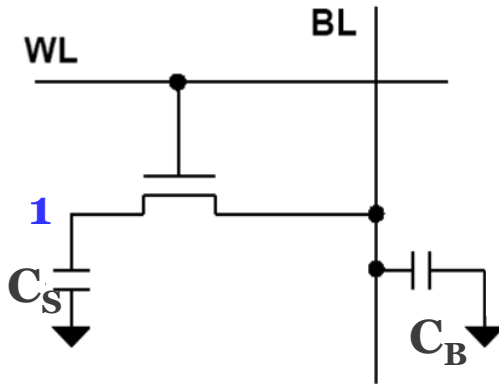
# DRAM

- ❑ One NMOS, One trench capacitor → highly dense !
- ❑ Trench capacitor is in itself an area of research



# DRAM READ OPERATION

- Say storage cap:  $C_S$  and bit line capacitance:  $C_B$
- Pre-charge bit line to  $V_{DD}/2$  (or  $V_{DD} \rightarrow$  both designs exist, power saving in half- $V_{DD}$ )



# DRAM READ

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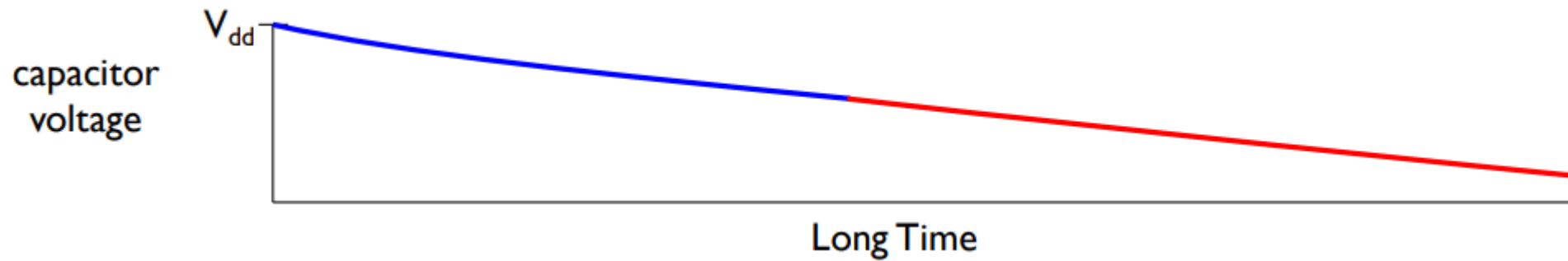
- ❑ Read is destructive: write back after a read from a buffer (Sense Amp output after read)
- ❑ After every read, mandatory write of the read data back to the row (before next read operation)





# DRAM REFRESH

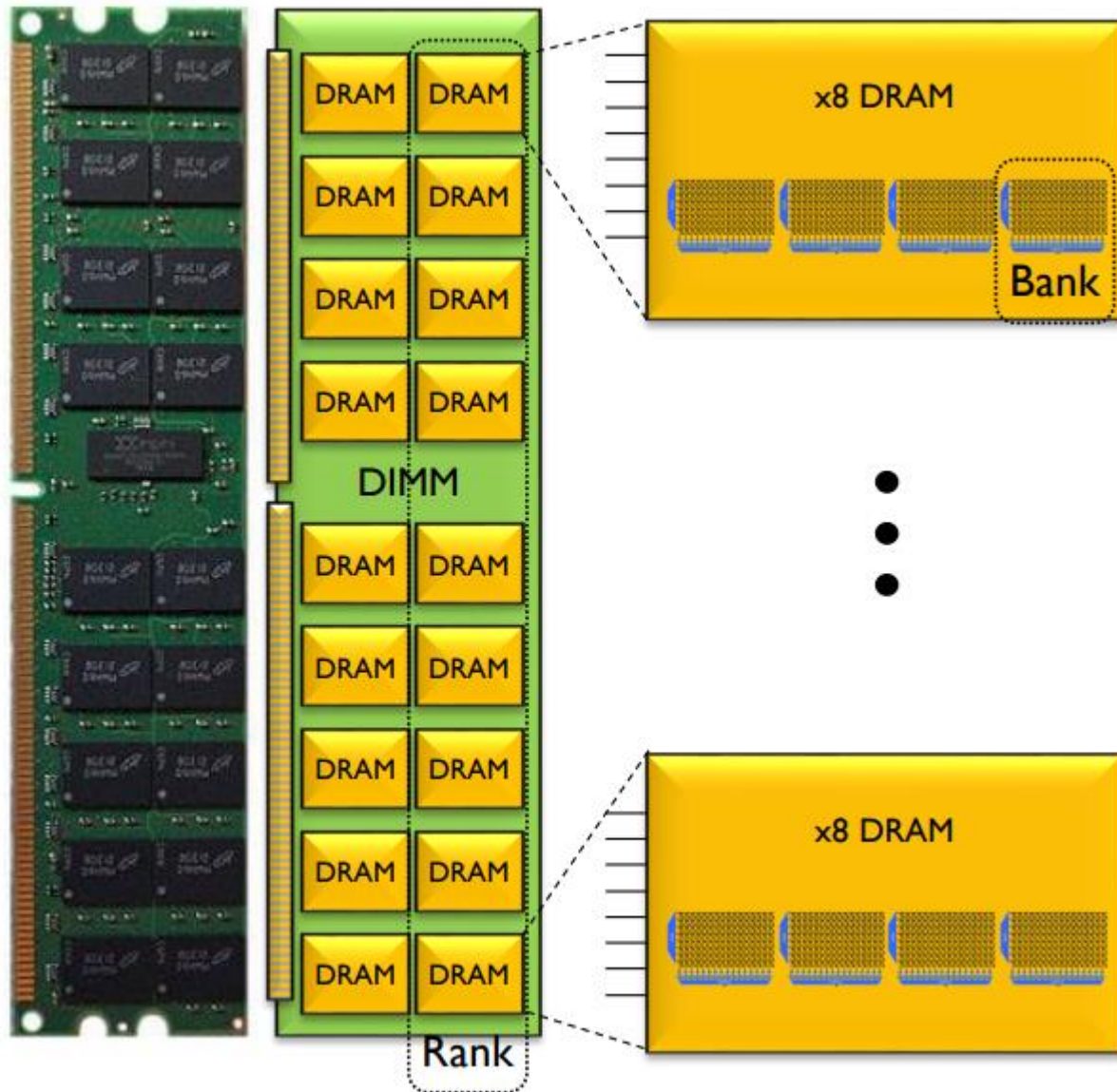
- ❑ If DRAM is not accessed: capacitor loses its content (leaky analog memory!)



- ❑ Therefore, DRAM must be regularly read/written
  - ❑ That is periodically perform a refresh
- ❑ DRAM refresh policies (to be handled by the memory controller):
  - ❑ Burst: stop all read/write access and refresh all content
  - ❑ Distributed: refresh one row at a time in a time-division-multiplexing



# TYPICAL DRAM ORGANIZATION



- ❑ Each DRAM: Multiple banks (for high bandwidth)
- ❑ Each DRAM: has 8-bits
- ❑ Each Rank: has 8-DRAM chips (64-bits)
- ❑ One additional DRAM for 8-bit ECC (error correction code)
- ❑ Read up on using banks in DRAM for high bandwidth using interleaved address map

# SERIAL MEMORY

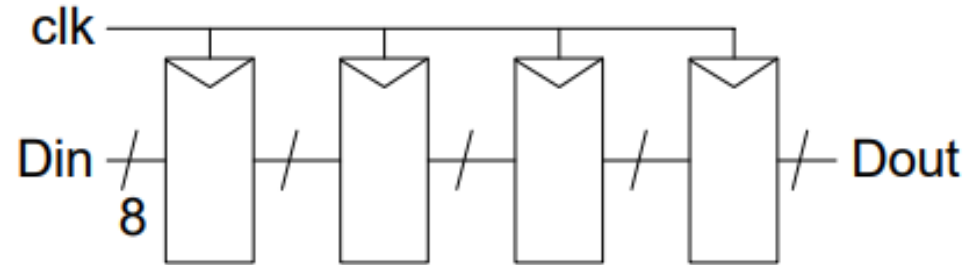
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- ❑ Serial access memory: do not use addressing (example: 1-bit DFF)
- ❑ Following types:
  - ❑ Shift registers
  - ❑ SIPO: Serial-In Parallel-Out
  - ❑ PISO: Parallel-In Serial-Out
  - ❑ Queues (FIFO, LIFO etc).

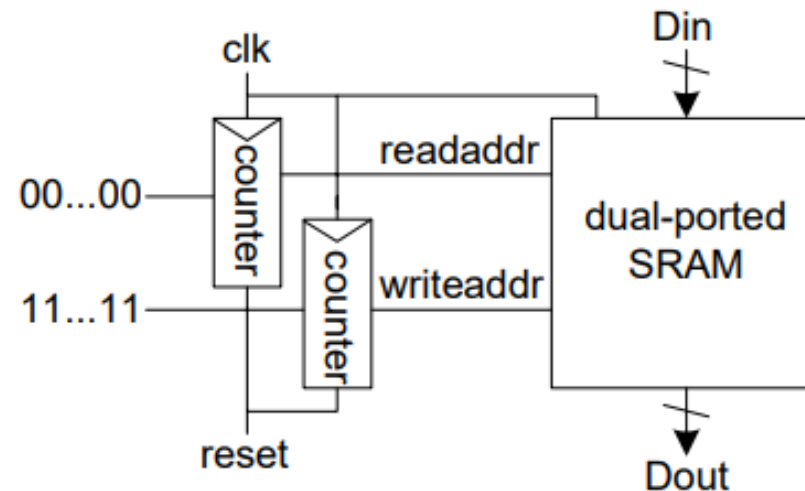


# SHIFT REGISTERS

- ❑ Delay in data storage (example  $Z^{-1}$  realization in DSP)
- ❑ Beware of hold violations !!!

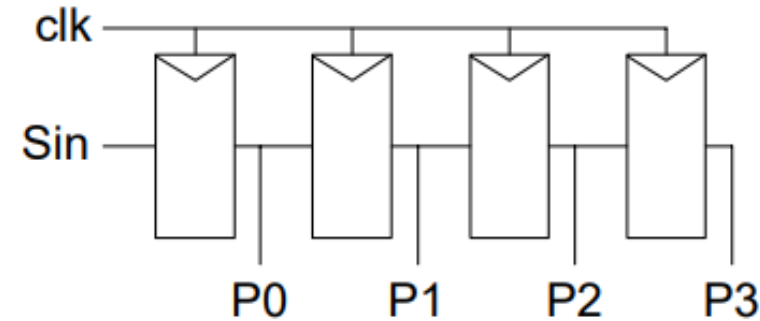


- ❑ DFF: not area efficient
- ❑ For higher density, use SRAMs
  - ❑ Move the pointers to read and write address

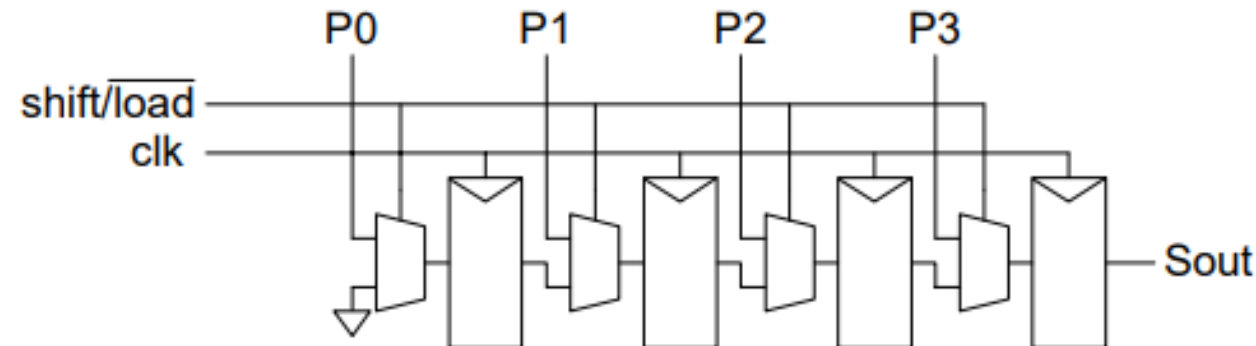


# SIPO AND PISO

- ❑ SIPO: 1-bit shift register  $\rightarrow$  after N cycles  $\rightarrow$  N bits parallel output



- ❑ PISO: Load N bit parallel data when shift = 0, then shift one bit per clk



# QUEUES

- ❑ FIFO/LIFO: built using SRAMs and counters
- ❑ Two counters: Read & Write pointer (RP, WP)

- ❑ FIFO:

- ❑ Initialize  $RP = WP$  (Queue is empty)
- ❑ Increment WP counter after every write
- ❑ Increment RP counter after every read
- ❑ Generate FULL signal based on WP and RP

- ❑ LIFO:

- ❑ Typically called “Stack”
- ❑ A single pointer (P) for read and write
- ❑ Depending on ascending/descending stack → increment/decrement address after write/read

